## Notice of References Cited Application/Control No. 10/017,160 Examiner Jason M Perilla Applicant(s)/Patent Under Reexamination LI ET AL. Page 1 of 1

## U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-5,900,834	05-1999	Kubinec, James J.	342/115
	В	US-6,795,515	09-2004	Riedle et al.	375/355
	O	US-6,304,116	10-2001	Yoon et al.	327/158
	D	US-5,272,729	12-1993	Bechade et al.	375/371
	E	US-5,457,719	10-1995	Guo et al.	375/373
	F	US-5,761,254	06-1998	Behrin, Michael N.	375/355
	G	US-5,272,390	12-1993	Watson et al.	327/141
	Н	US-4,713,621	12-1987	Nakamura et al.	327/152
	ı	US-4,443,766	04-1984	Belton, Jr., John P.	327/91
	J	US-5,289,135	02-1994	Hoshino et al.	327/3
	К	US-5,708,382	01-1998	Park, Sung Man	327/277
	L	US-			
	М	US-			

## FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	0					
	Р					
	Q					
	R					
	s					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)		
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	x			

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.